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KR			4,958,213	9-18-90	Eklund	, et aL	257	378			
			5,006,913	4-9-91	Sugaha	ra, et al.	25	7 67			
	十		5,060,030	10-22-91	Hoke, e	t al.	25-	1 194			
			5,081,513	1-14-92	Jackson	o, et al.	25	1 57			
KI	2		5,108,843	4-28-92	Ohtaka	, et al.	428	446			
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KR US 2002/0086497 A1 7-4-02 Kwok 438 424											
	US 2002/0090791 A1				Doyle,	et al.	438	.396			
	US 2003/0032261 A1			2-13-03	Yeh, et	al.	438	451			
KR			US 2003/0040158 A1	2-27-03	Saitoh		438	279			
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		Т	Gregory Scott, et al., "N	MOS Drive Cur	rent Redu	iction Caused by Transisto					
			International Electron D	evices ivieeding,	J4.4.1, IE	ee, september 1999.					
			F. Ootsuks, et al., "A Hi Application." Internation	ighly Dense, Hig onal Electron De	h-Perforn vices Mee	nance 130nm Node CMOS eting, 23.5.1, IEEE, April 20	Technology 000.	for Large Scale	System-on-s-Chlp		
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KR		3,602,841	8-31-71	McGro	ddy	33	1	107 G		-AAT-SAAC
		4,665,415	5-12-87	Esaki, e	et aL	125	7	190		
		4,853,076	8-1-89	Tsaur,	et al.	43	8	479		
		4,855,245	8-8-89	Neppl,	et al.	43	88	207		
KR		4,952,524	8-28-90	Lee, et	al.	49	8	437	437	
			U.S. PATENT	r applica	ATION PUBLICATIONS				·	
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KR		US 2001/0009784 A1	7-26-01	Ma, et	al.	438	3	197		
		US 2002/0063292 A1	5-30-02	Armstr	ong, et al.	25	7	367		.
		US 2002/0074598 A1	Doyle,	et al.	25	7	345			
KR		US 2002/0086472	7-4-02	Roberd	ls, et al.	43	8	197		
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	ŀ	Devices Meeting, 26, 8	, 1, IEEE, Septem	ber 1998.						
<u> </u>	_	Kern Rim, et al., "Cha	racteristics and D	evice Des	Ign of Sub-100 nm Straine E, pp. 98-99.	d Si N- an	d PM	OSFETs." 20	02 Sympo	sium o
		A POL 1 SCHOOLOGY DISC	er of Technical Le	pers, IEE	≈, bh. 10 <u>.11</u> ,					
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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE		NAMB	c	LASS	SUBCLASS	FILING IF APPRO	
KR		5,134,085	7-28-92 °	Gilgen	, et al.	4	3 8	840		ن جس وس
		5,310,446	5-10-94	Konish	ii, et aL	1	17	58		
_		5,354,695	10-11-94	Leedy		4	38	411		
		5,371,399	12-6-94	Burro	ighes, et al.	2	57	451		
KR		5,391,510	2-21-95	Hsu, et	al.	1	138	301		
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KR		US 2003/0057184 A1	3-27-03	Yu, et	al.	a	16	79		
NP		US 2003/0067035 A1	4-10-03	Tews,	et al.	a	57	333		
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		Shinya Ito, et al., "Me International Electron								
		A. Shimizu, et al., "Lo International Electron	cal Mechanical-S Devices Meeting	tress Con , IEEE, M	trol (LMC): A New To larch 2001.	echnique fo	r CMO	S-Performance	Enhancer	nent."
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KR		5,459,346	10-17-95	Asakaw	a, et aL	25	7 347	
		5,471,948	12-5-95	Burrou	ghes, et al.	433	93	
		5,557,122	9-17-96	Shrivas	tava, et al.	25	309	
		5,561,302	10-1-96	Candel	aria	25	7 24	
KR		5,565,697	10-15-96	Asakav	/a, et al.	25	1 347	
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		Devices intectug, s.s.1,	ibbb, restumy					
		G. Zhang, et al., "A Nev IEEE Transactions on F	v'Mixed-Mode' Electron Devices,	Reliability vol. 49, n	Degradation Mechanism o. 12, December 2002, pp. 2	n Advance 1151-56.	d Si and SiGe Bi	polar Transistors.
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KR		5,571,741	11- 5-9 6	Leedy		438	27		
		5,592,007	1-7-97	Leedy		25	1 347		
		5,592,018	1-7-97	Leedy		25	1 619		
		5,670,798	9-23-97	Schetz	na	25	7 96		
KR		5,679,965	10-21-97	Schetzi	ina	25	1 103		
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		H.S. Momose, et al., "T by MOS Structures." I	emperature Dep Paper 6.2, pp. 140	endence o D-143.	f Emitter-Base Reverse St	ress Degrad	enou sug 165 Me	CHRUSH Analyzed	
		C.J. Huang, et al., "Ter Transistors." IEEE 19	nperature Depen 91 Bipolar Circu	dence and to	d Post-Stress Recovery of lechnology Meeting 7.5, pp.	Hot Electron 170-173.	Degradation Ef	fects in Bipolar	
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KR		5,683,934	11-4-97	Candel	aria	438	151	
		5,840,593	11-24-98	Leedy		438	6	
		5,861,651	1-19-99	Brasen	, et al.	25	All	
		5,880,040	3-9-99	Sun, et	al.	438	769	
KR		5,940,716	8-17-99	Jin, et	al.	438	424	
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					SiGe HBTs Following R	•	•	
		Z. Yang, et al., "Avala Transistors." Pp. 1-5.	nche Current Ind	uced Hot	Carrier Degradation in	200 GHz SiGe	Heterojunction	Bipolar
								
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KR		5,940,736	8-17-99	Brady,	et al.		438	787		
		5,946,559	8-31-99	Leedy			438	157		
		5,960,297	9-28-99	Saki			438	424		·
		5,989,978	11-23-99	Peidou	8		432	3 436		
KR		6,008,126	12-28-99	Leedy			438	667		
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		H. Li, et al., "Design of Systems." 2003 IEEE	W-Band VCOs v GaAs Digest, pp.	with High 263-66.	Output Powe	r for Potentia	Application	on in 77 GHz Au	omotive R	ader
	寸	H. Wurzer, et al., "And Devices, vol. 41, no. 4,	nealing of Degrad April 1994, pp. 53	ed npn-T 33-38.	ransistors- M	echanisms and	Modeling	." IEEE Transa	ctions on E	Jectron
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KR		6,025,280	2-15-00	Brady,	et al.	438		
		6,046,464	4-4-00	Schetzi	na 	25	196	
		6,066,545	5-23-00	Doshi,	et al.	43	8 439	
		6,090,684	7-18-00	Ishitsu	ka, et al.	43	8 424	
KR		6,107,143	8-22-00	Park, e	t al.	432	296	
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		B. Doyle, et al., "Recov Letters, vol. 13, no. 1,	ery of Hot-Carri January 1992, pp.	er Damag 38-40.	e in Reoxidized Nitrided (oxide MOSF	ETa." IEEE Ele	ectron Device
		W 6 W annual of all III	Salvela of the Te	mneretur	a Dependence of HoteCari	der-Induced	Degradation in	Bipolar Transistor
		for Bi-CMOS." IEEE	Transactions on l	Electron	e Dependence of Hot-Cari Devices, vol. 41, no. 6, Jun	e 1994, pp. 9	78-987.	•
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KR		6,117,722	9-12-00	Wuu, e	t al.	437	3 238		
		6,133,071	10-17-00	Nagai		438	122		
		6,165,383	12-26-00	Chou		252	. 301.16		
		6,221,735	4-24-01	Manley	y, et al.	438			
KR		6,228,694	5-8-01	Doyle,	et al.	438	199		
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KR		6,246,095	6-12-01	Brady,	et al.	25	7 411		
		6,255,169	7-3-01	Li, et a	l.	438	3 264		
		6,261,964	7-17-01	Wu, et	al.	438	705		
		6,265,317	7-24-01	Chiu, e	et al.	43	8 711		
KR		6,274,444	8-14-01	Wang	•	435	8 299		
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KR		6,281,532	8-28-01	Doyle,	et al.	251		
		6,284,623	9-4-01	Zhang,	et al.	438	424	
		6,284,626	9-4-01	Kim		738	3 433	
		6,319,794	11-20-01	Akatsu	, et al.	438	424	
KR		6,361,885	3-26-02	Chou		428	690	
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			6,36	8,931	4-9-02	Kuhn,	et al.	43	8	359		
			6,40	3,486	6-11-02	Lou		43	8	694		
			6,40	3,975	6-11-02	Brunn	er, et al.	25	7	15		
KI	R		6,40	6,973	6-18-02	Lee		43	8	416		
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Application Number

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